



Your Trusted Partner in Semiconductor Testing

TWSE:6515

Investor Presentation

2026.10.19

Safe Harbor Notice

This presentation may contain forward-looking statements. All statements, other than statements of historical facts, that address activities, events or developments that WinWay Technology Co., Ltd. expects or anticipates will or may occur in the future (including but not limited to projections, targets, estimates and business plans) are forward-looking statements.

WinWay's actual results or developments may differ materially from those indicated by these forward-looking statements as a result of various factors and uncertainties, including but not limited to market demand, price fluctuations, competition, change in legal, government policies, financial market conditions, and other risks and factors beyond our control.

This presentation does not undertake any obligation to publicly update any forward-looking statements to reflect events or circumstances after the date on which any such statement is made or to reflect the occurrence of unanticipated events.

Company Information

**Kaohsiung
Headquarter**

Founded

2001.4 .10

Capital Stock

NTD 364,447,820

Employees

1602

Chairman & CEO

Mark Wang

Business Operation

Design, manufacture, sale and service of test interface products

Registered Address

No.68, Chuangyi S. Rd, Nanzi Dist.
Kaohsiung City, Taiwan



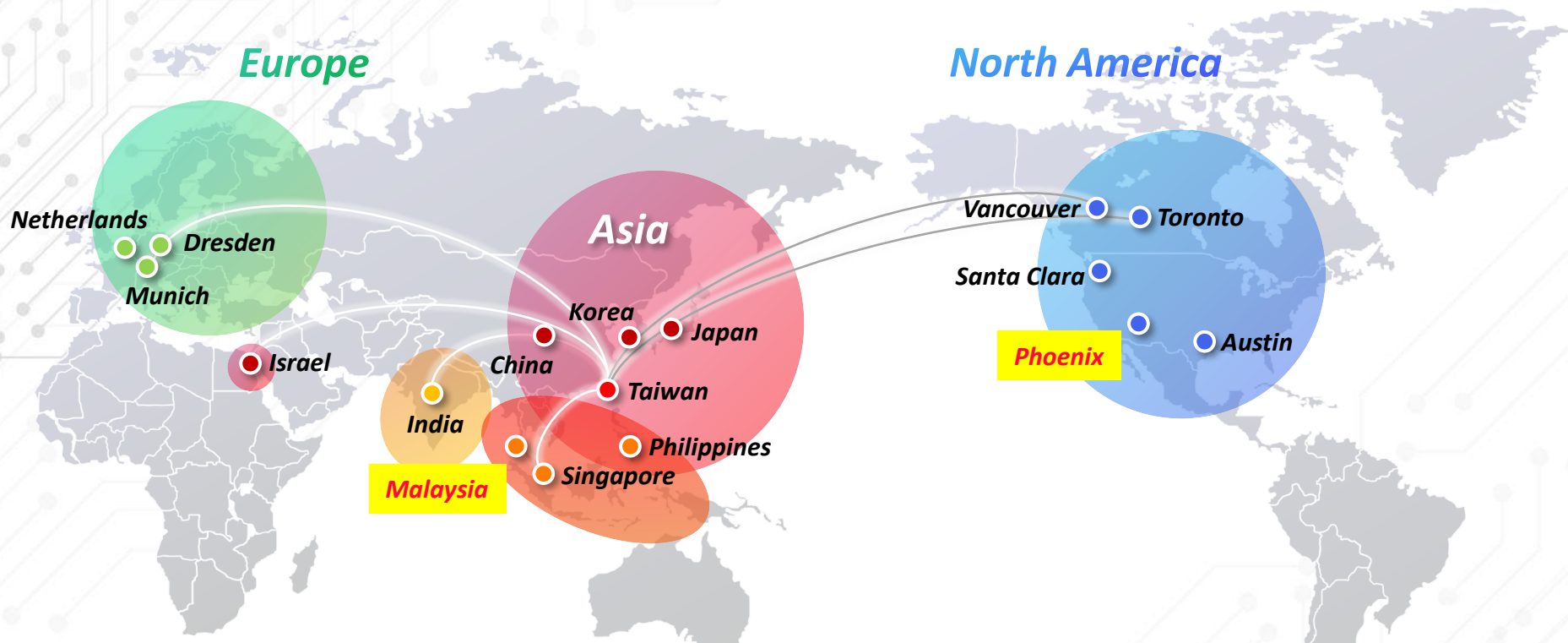
USA Branch Office



Hsinchu Branch Office



Global Service & Support Network



Accelerating Expansion Socket Capacity

Renwu Facility I

Operational from May. 2026

Renwu Facility II

Ground-breaking : 2026.5.29

Begin Operation : 2027 Q2

Total Area
Approx. **6300** ping

WinWay Socket Capacity

Set / Month

5,000-pin equivalent sockets



Accelerating Expansion Spring Probe Capacity



Cost Optimization

Balanced insourcing, better cost structure



Self-Sufficiency

Autonomy of critical process technology



Quality Assurance

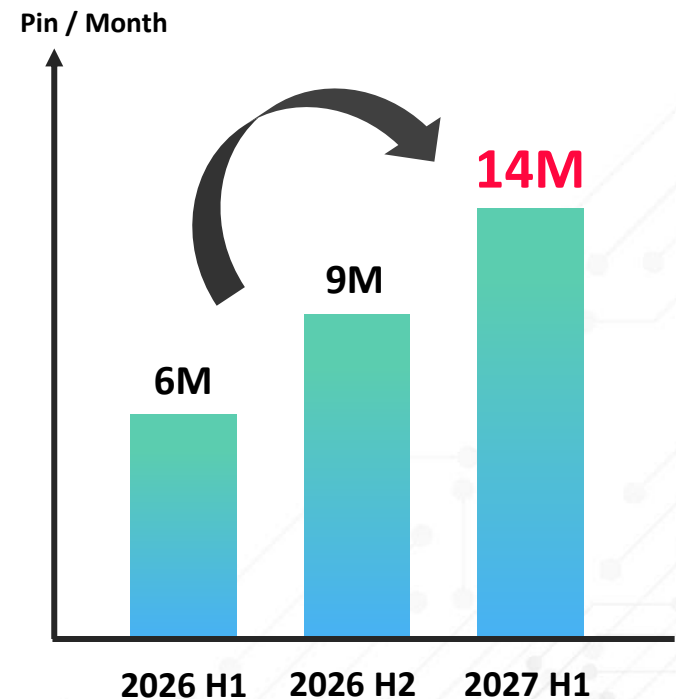
Greater customer experience



Operational Resilience

More flexible, agile lead time

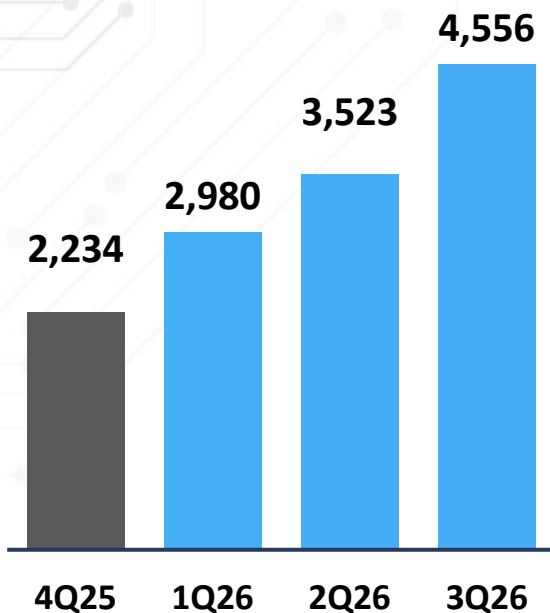
WinWay Spring Probe Capacity



Revenue Trend

QUARTERLY REVENUE

(NTD MILLION)

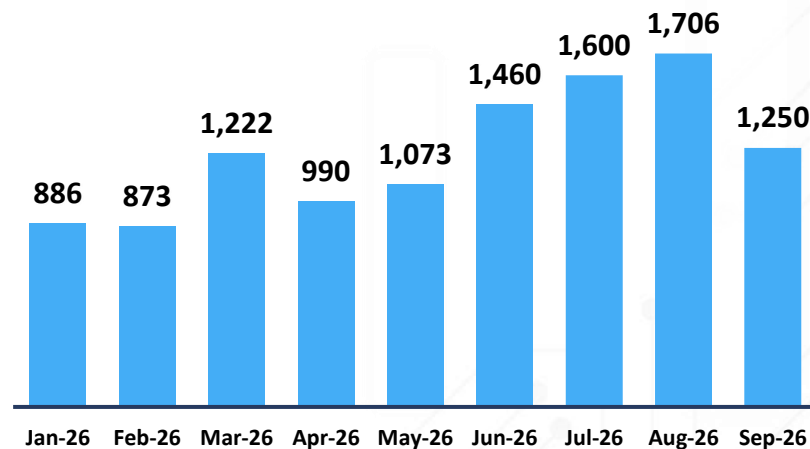


YoY	4Q25	1Q26	2Q26	3Q26
YoY	45%	30%	131%	153%

QoQ	4Q25	1Q26	2Q26	3Q26
QoQ	24%	33%	18%	29%

MONTHLY REVENUE

(NTD MILLION)



YoY	Jan-26	Feb-26	Mar-26	Apr-26	May-26	Jun-26	Jul-26	Aug-26	Sep-26
YoY	33%	-4%	69%	51%	120%	288%	156%	233%	88%

MoM	Jan-26	Feb-26	Mar-26	Apr-26	May-26	Jun-26	Jul-26	Aug-26	Sep-26
MoM	-5%	-2%	40%	-19%	8%	36%	10%	7%	-27%

Profitability Trend

2026 Q1-Q2 EPS

(NT\$) **38.24**

EPS

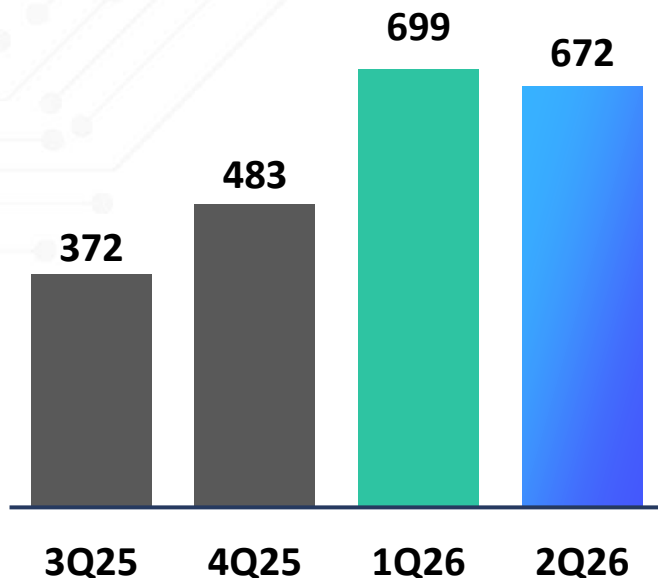
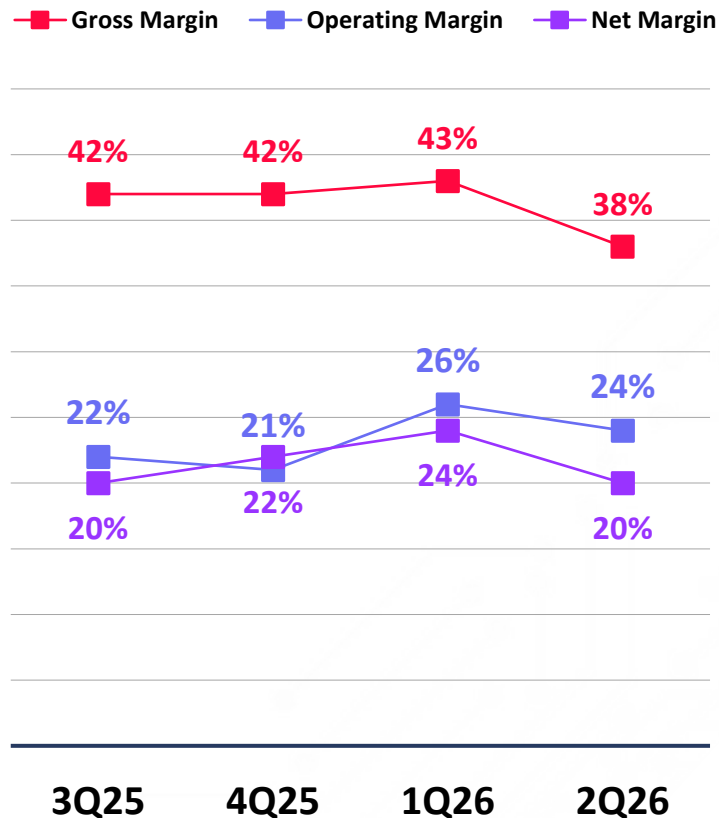
10.43

13.53

19.54

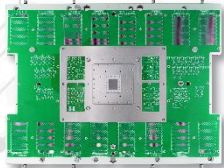
18.7

NET INCOME (NTD M)



Revenue by Product Mix

2026 H1



Probe Card

27 %



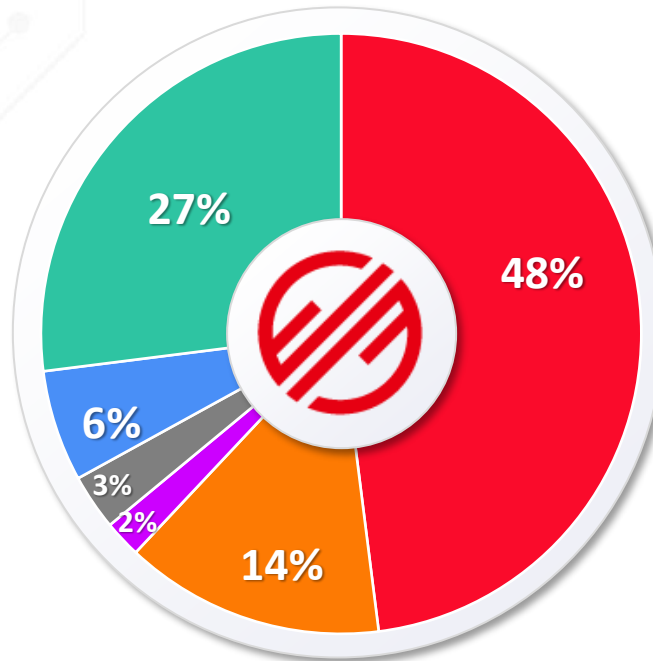
Contact
Element

6 %



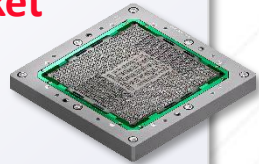
Others

3 %



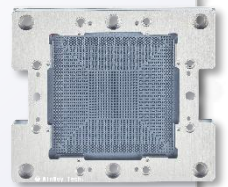
Coaxial Socket

48 %



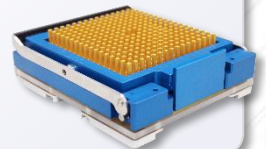
PoP & Plastic
Socket

14 %



Burn-in Socket

2 %

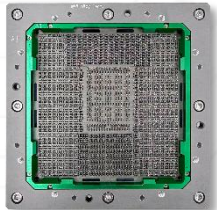


Revenue by End Market

2026 H1



HyperSocket™



Coaxial Socket

HPC & AI

70%



**Networking
Auto / Others**

18%

Plastic Socket

Smart Phone

8%

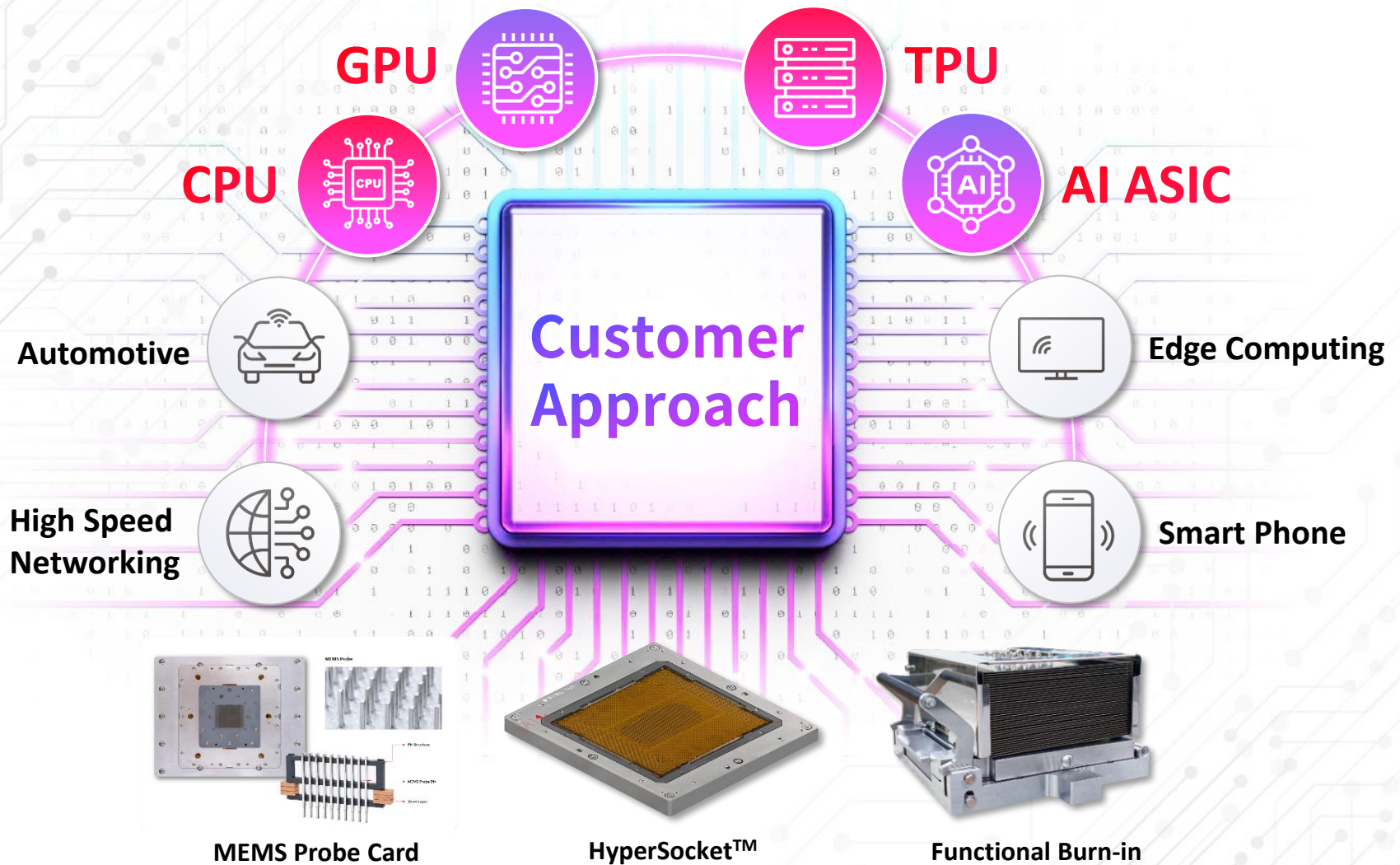
POP Plastic Socket

PC & Gaming

4%

POP Plastic Socket

In for the Long Haul



Innovative Semiconductor Test Interface Solution

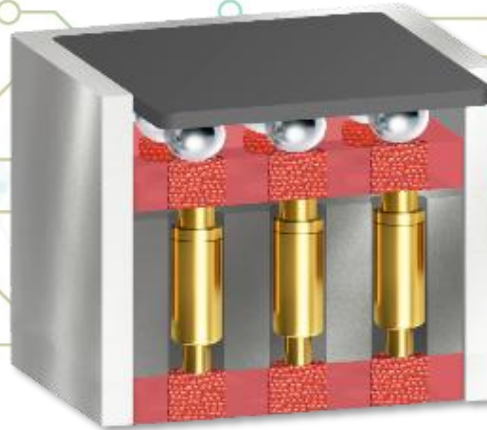
HyperSocket™-Dual Film

Patent NO.

TWI862047
TWI884802
TWI862191
TWI901161
TWI922268
TWI923382
CN220584352

Patent Pending

USA
Malaysia



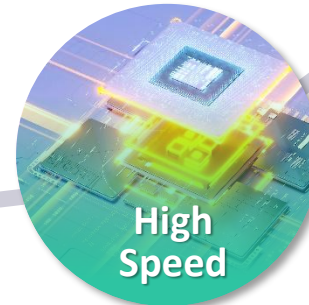
Large Package

- Larger contact area
- Improved heat dissipation
- Enhanced test stability



High Power

- Various current pathways
- Mitigating temperature rise



High Speed

- Full metal shielding, short-loop design
- Test speed above 224Gbps

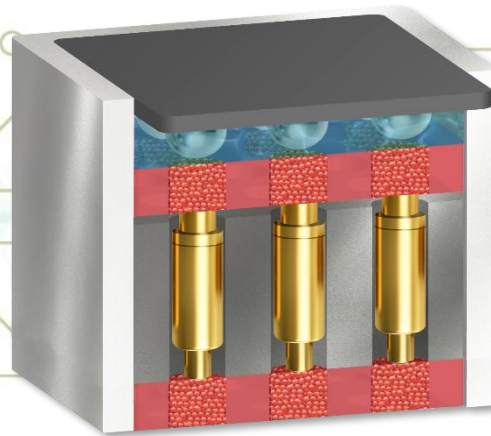


High Pin Counts

- Zero Pre-load design
- Reduced maintenance cost

Innovative Semiconductor Test Interface Solution

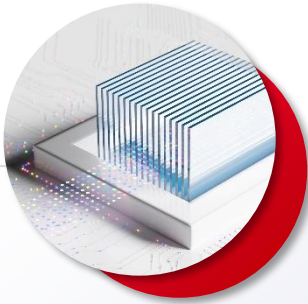
Liquid Cooling Socket



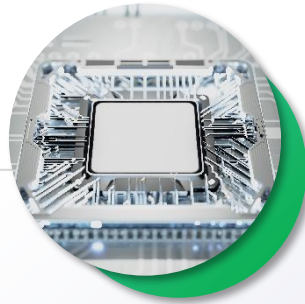
Patent NO.

TWI901181

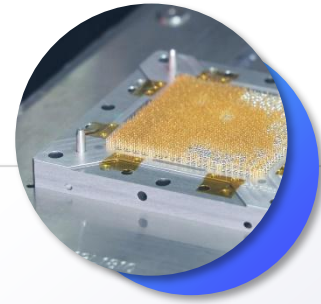
US12625162



**Extraordinary heat
dissipation**



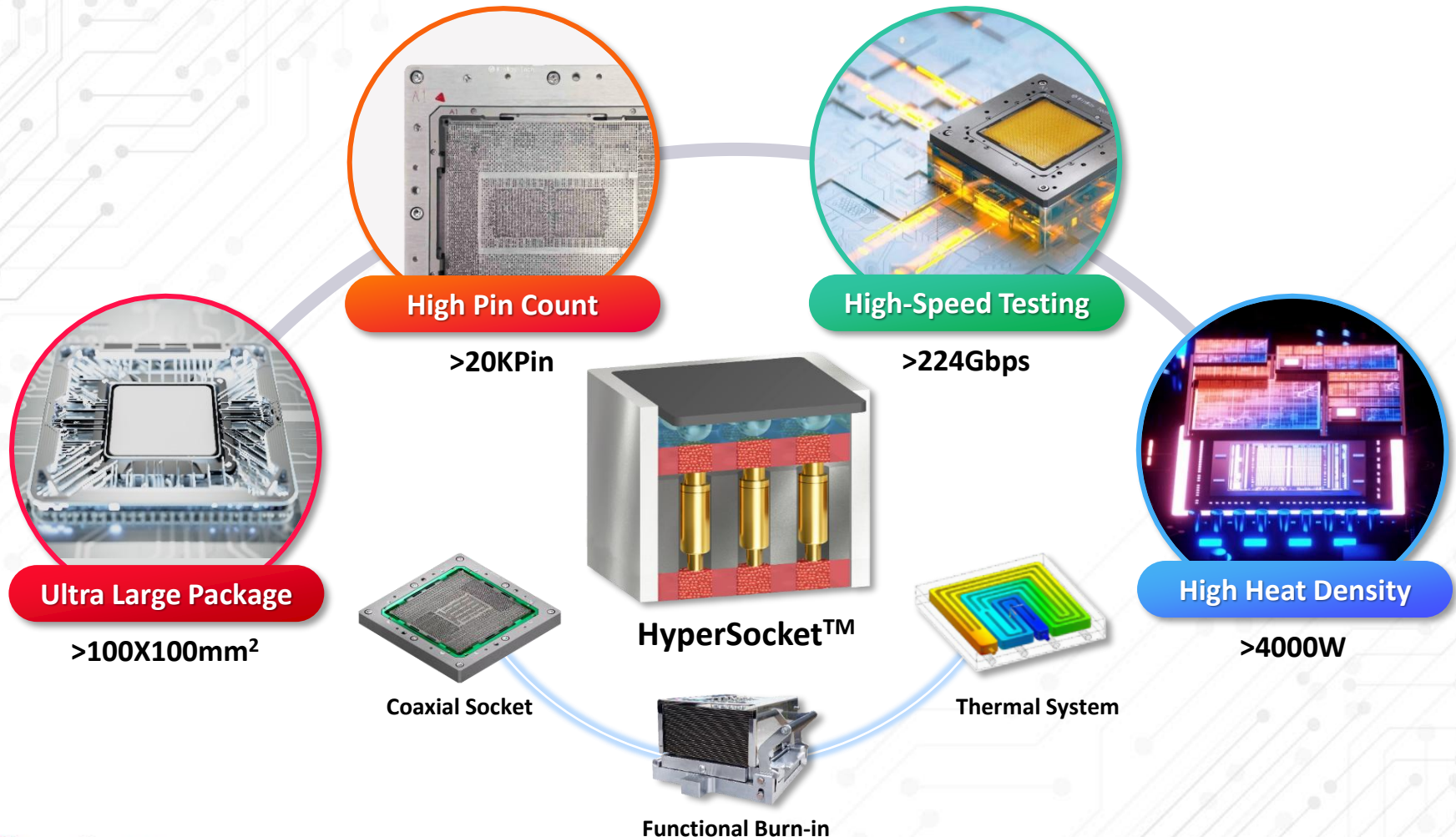
**Improved Test Stability
For Advanced Packaging**



**Extend Spring
Probe Lifespan**

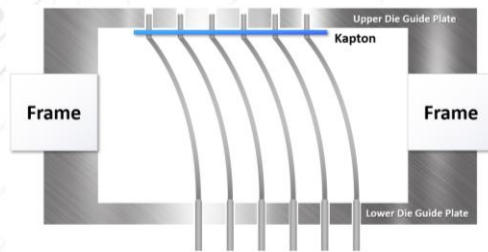
Accelerated SLT Demand Driven by AI

Comprehensive solution for all test insertions



Greater Importance on Chip Probing

At Speed Test and K.G.D

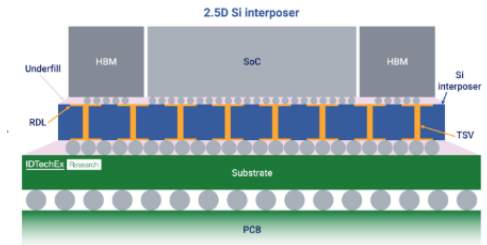


Cobra



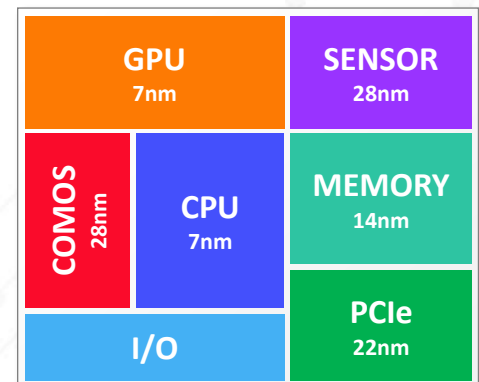
MEMS

Pin Count	Less, limited to probe force design	★ Higher (More flexible to design)
CCC(A)	2.2 @ 4mil probe diameter	★ 2.2 @ 3mil probe diameter
High Speed	32G	★ 112G
Force(g)	2~25	★ 1.5 ~ 4.5
Pitch (um)	80~200	★ 40~200
Operating Temp.	- 50°C to 150°C	★ - 50°C to 175°C



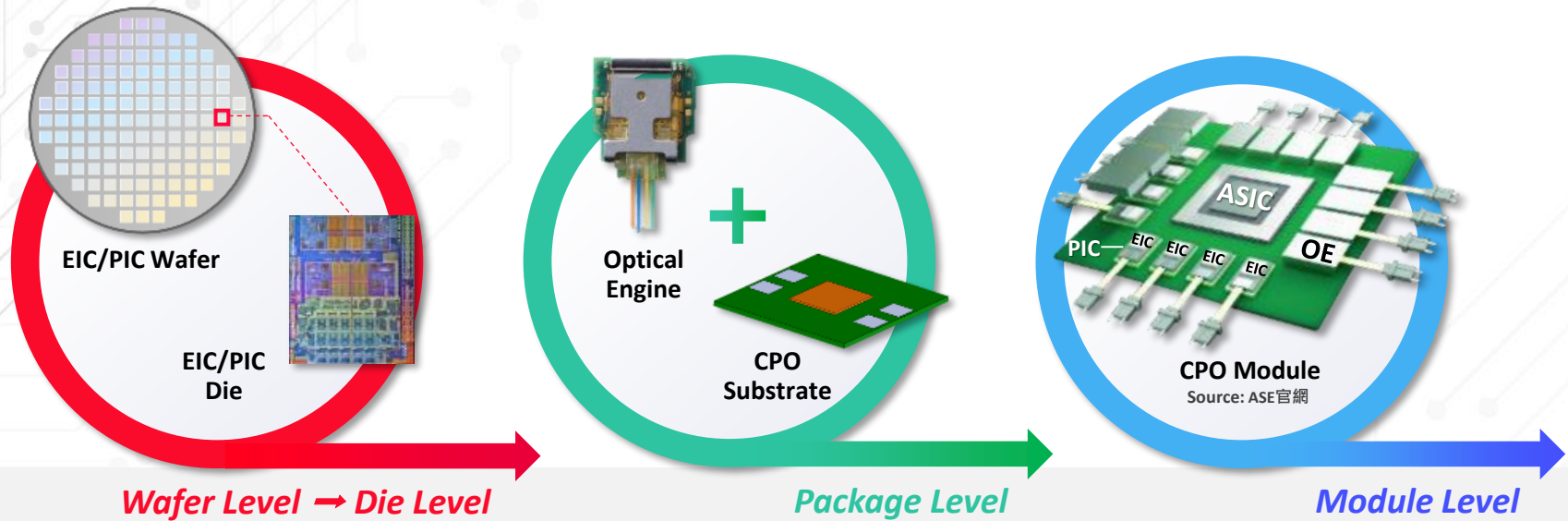
Source : IDTechEx Research

Chiplet Multiple Probe Card Demand

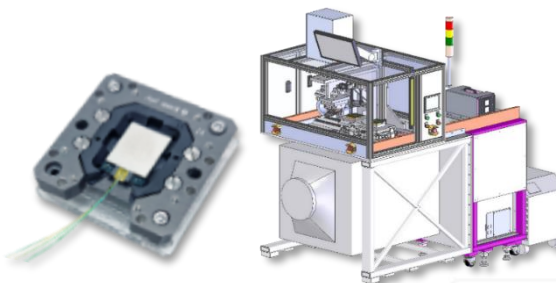


Source : Trend Force

Co-Packaged Optics Test Solution

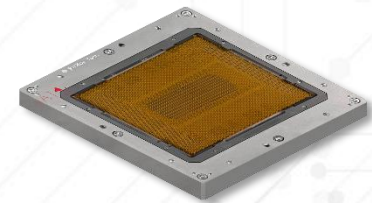


WLCSP Probe Head
(PIC & EIC Wafer test)



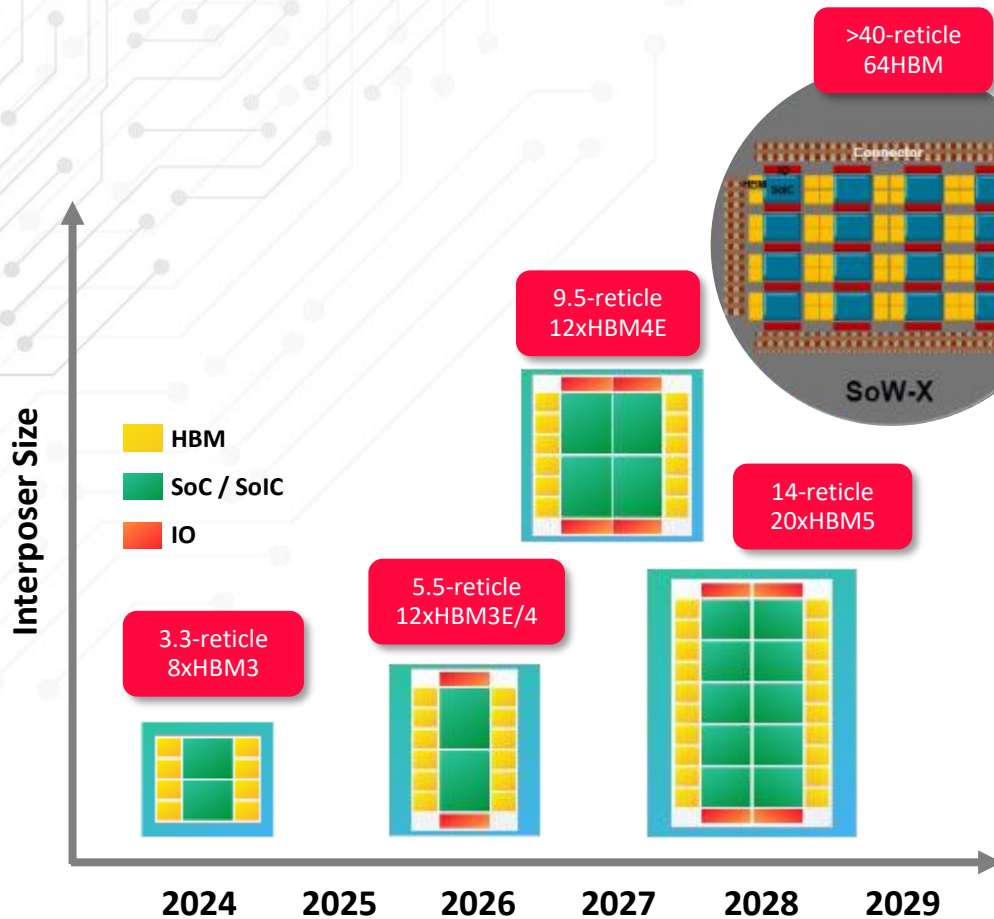
Optical and Electrical
Test Socket
(Optical Engine)

Double Sided
Probing System

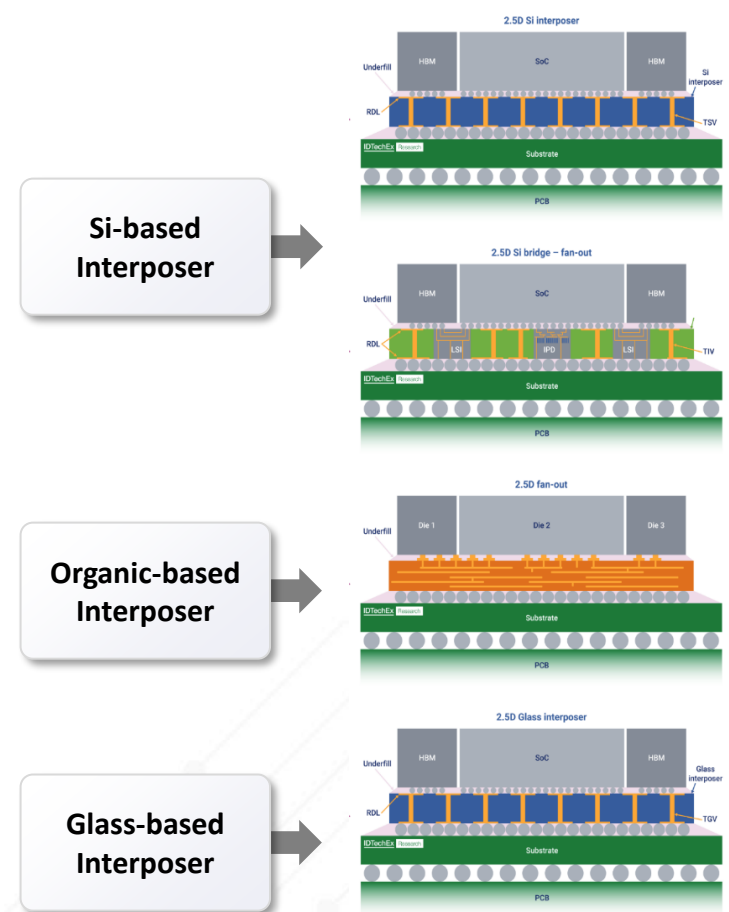


HyperSocket™

Performance Breakthrough: Evolution of Advanced Packaging

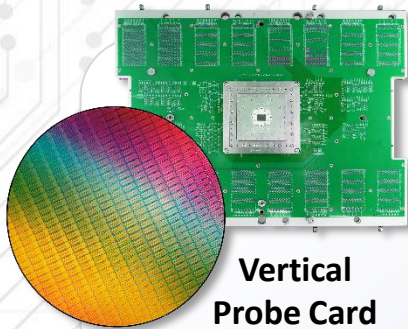


Source : TSMC

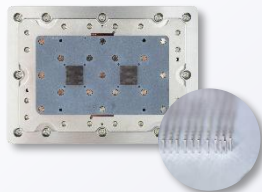


Source : IDTechEx Research

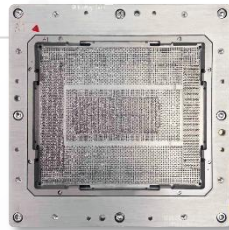
Your Trusted Partner in Semiconductor Testing



Vertical
Probe Card



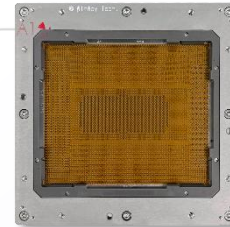
MEMS Probe Card



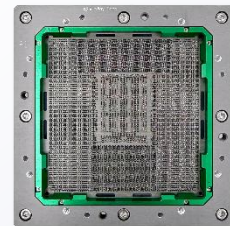
Coaxial Socket



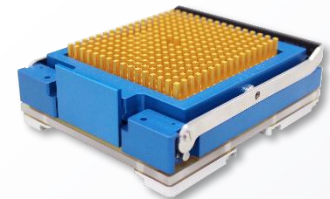
PoP Socket



HyperSocket™



Coaxial Socket



Production
Burn-in Socket

Wafer Sort

Final Test

SLT & SFT

Functional
Burn-in

DFT Design For Testing **DFM** Design For Manufacturing

TWSE:6515

Q&A



WinWay

Your Trusted Partner in Semiconductor Testing

TWSE:6515

THANK YOU

You may contact WinWay Technology via

sales@winwayglobal.com

+886 7 361 0999 / +886 3 656 8282

www.winwayglobal.com